

N-channel 650 V, 0.014 Ω typ., 130 A, MDmesh™ V Power MOSFET in a ISOTOP package

Datasheet - preliminary data

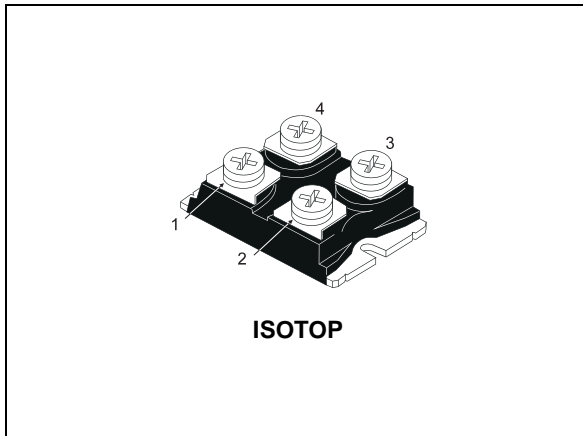
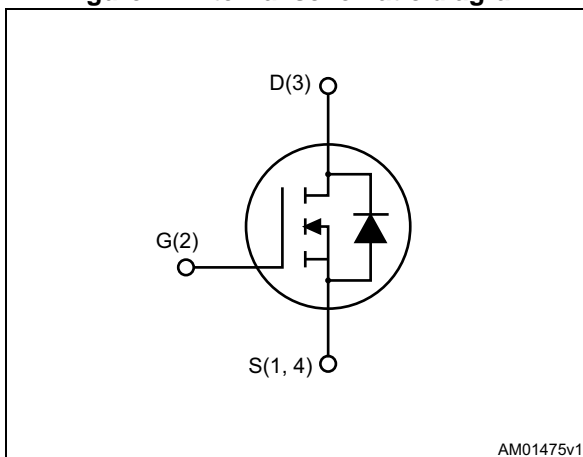


Figure 1. Internal schematic diagram



Features

| Order code | $V_{DS} @ T_{jmax}$ | $R_{DS(on) max}$ | I_D |
|-------------|---------------------|------------------|-------|
| STE139N65M5 | 710 V | 0.017 W | 130 A |

- Very low $R_{DS(on)}$
- Higher V_{DSS} rating
- Higher dv/dt capability
- Excellent switching performance
- 100% avalanche tested

Applications

- Switching applications

Description

This device is an N-channel MDmesh™ V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product has extremely low on-resistance, which is unmatched among silicon-based Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

Table 1. Device summary

| Order code | Marking | Packages | Packaging |
|-------------|----------|----------|-----------|
| STE139N65M5 | 139N65M5 | ISOTOP | Tube |

Contents

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1 Electrical ratings

Table 2. Absolute maximum ratings

| Symbol | Parameter | Value | Unit |
|----------------|---|-------------|------------------|
| V_{GS} | Gate- source voltage | ± 25 | V |
| I_D | Drain current (continuous) at $T_C = 25\text{ }^\circ\text{C}$ | 130 | A |
| I_D | Drain current (continuous) at $T_C = 100\text{ }^\circ\text{C}$ | 78 | A |
| $I_{DM}^{(1)}$ | Drain current (pulsed) | 520 | A |
| P_{TOT} | Total dissipation at $T_C = 25\text{ }^\circ\text{C}$ | 672 | W |
| I_{AR} | Max current during repetitive or single pulse avalanche (pulse width limited by T_{JMAX}) | 17 | A |
| E_{AS} | Single pulse avalanche energy (starting $T_j = 25\text{ }^\circ\text{C}$, $I_D = I_{AR}$, $V_{DD} = 50\text{V}$) | 2400 | mJ |
| $dv/dt^{(2)}$ | Peak diode recovery voltage slope | 15 | V/ns |
| T_{stg} | Storage temperature | - 55 to 150 | $^\circ\text{C}$ |
| T_j | Max. operating junction temperature | 150 | $^\circ\text{C}$ |

1. Pulse width limited by safe operating area.
2. $I_{SD} \leq 130\text{ A}$, $di/dt = 400\text{ A}/\mu\text{s}$, $V_{DD} = 400\text{ V}$, $V_{DS(\text{peak})} < V_{(BR)DSS}$.

Table 3. Thermal data

| Symbol | Parameter | Value | Unit |
|----------------|---|-------|---------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case max | 0.186 | $^\circ\text{C}/\text{W}$ |
| $R_{thj-amb}$ | Thermal resistance junction-ambient max | 30 | $^\circ\text{C}/\text{W}$ |

2 Electrical characteristics

($T_C = 25\text{ °C}$ unless otherwise specified)

Table 4. On /off states

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|---------------|--|--|------|-------|-----------|--------------------------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage | $I_D = 1\text{ mA}$, $V_{GS} = 0$ | 650 | | | V |
| I_{DSS} | Zero gate voltage drain current ($V_{GS} = 0$) | $V_{DS} = 650\text{ V}$ $V_{DS} = 650\text{ V}$, $T_C = 125\text{ °C}$ | | | 10 100 | μA μA |
| I_{GSS} | Gate-body leakage current ($V_{DS} = 0$) | $V_{GS} = \pm 25\text{ V}$ | | | ± 100 | nA |
| $V_{GS(th)}$ | Gate threshold voltage | $V_{DS} = V_{GS}$, $I_D = 250\text{ }\mu\text{A}$ | 3 | 4 | 5 | V |
| $R_{DS(on)}$ | Static drain-source on- resistance | $V_{GS} = 10\text{ V}$, $I_D = 65\text{ A}$ | | 0.014 | 0.017 | Ω |

Table 5. Dynamic

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|-------------------|---------------------------------------|---|------|-------|------|----------|
| C_{iss} | Input capacitance | $V_{DS} = 100\text{ V}$, $f = 1\text{ MHz}$, $V_{GS} = 0$ | - | 15600 | - | pF |
| C_{oss} | Output capacitance | | - | 365 | - | pF |
| C_{riss} | Reverse transfer capacitance | | - | 9 | - | pF |
| $C_{o(tr)}^{(1)}$ | Equivalent capacitance time related | $V_{GS} = 0$, $V_{DS} = 0\text{ to }520\text{ V}$ | - | 1559 | - | pF |
| $C_{o(er)}^{(2)}$ | Equivalent capacitance energy related | $V_{GS} = 0$, $V_{DS} = 0\text{ to }520\text{ V}$ | - | 360 | - | pF |
| R_G | Intrinsic gate resistance | $f = 1\text{ MHz}$ open drain | - | 1.2 | - | Ω |
| Q_g | Total gate charge | $V_{DD} = 520\text{ V}$, $I_D = 65\text{ A}$, $V_{GS} = 10\text{ V}$ (see Figure 15) | - | 363 | - | nC |
| Q_{gs} | Gate-source charge | | - | 88 | - | nC |
| Q_{gd} | Gate-drain charge | | - | 164 | - | nC |

- $C_{o(tr)}^{(1)}$ is a constant capacitance value that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .
- $C_{o(er)}^{(2)}$ is a constant capacitance value that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS} .

Table 6. Switching times

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit |
|--------------|--------------------|---|------|------|------|------|
| $t_{d(v)}$ | Voltage delay time | $V_{DD} = 400\text{ V}$, $I_D = 80\text{ A}$, $R_G = 4.7\ \Omega$, $V_{GS} = 10\text{ V}$ (see Figure 16) (see Figure 19) | - | 295 | - | ns |
| $t_{r(v)}$ | Voltage rise time | | - | 56 | - | ns |
| $t_{f(i)}$ | Current fall time | | - | 37 | - | ns |
| $t_{c(off)}$ | Crossing time | | - | 84 | - | ns |

Table 7. Source drain diode

| Symbol | Parameter | Test conditions | Min. | Typ. | Max. | Unit | |
|-----------------|-------------------------------|--|--|------|------|------|---------------|
| I_{SD} | Source-drain current | $I_{SD} = 130\text{ A}$, $V_{GS} = 0$ | - | | 130 | A | |
| | Source-drain current (pulsed) | | | | 520 | A | |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) | | - | | 520 | A | |
| $V_{SD}^{(2)}$ | Forward on voltage | | - | | 1.5 | V | |
| t_{rr} | Reverse recovery time | | - | 570 | | ns | |
| Q_{rr} | Reverse recovery charge | | $I_{SD} = 130\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ $V_{DD} = 100\text{ V}$ (see Figure 16) | - | 15 | | μC |
| I_{RRM} | Reverse recovery current | | - | 53 | | A | |
| t_{rr} | Reverse recovery time | | $I_{SD} = 130\text{ A}$, $di/dt = 100\text{ A}/\mu\text{s}$ | - | 720 | | ns |
| Q_{rr} | Reverse recovery charge | | $V_{DD} = 100\text{ V}$, $T_j = 150\text{ }^\circ\text{C}$ (see Figure 16) | - | 24 | | μC |
| I_{RRM} | Reverse recovery current | (see Figure 16) | - | 68 | | A | |

1. Pulse width limited by safe operating area.
2. Pulsed: pulse duration = 300 μs , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

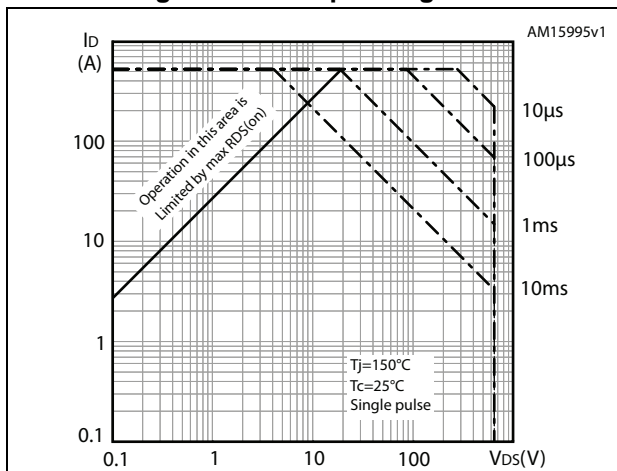


Figure 3. Thermal impedance

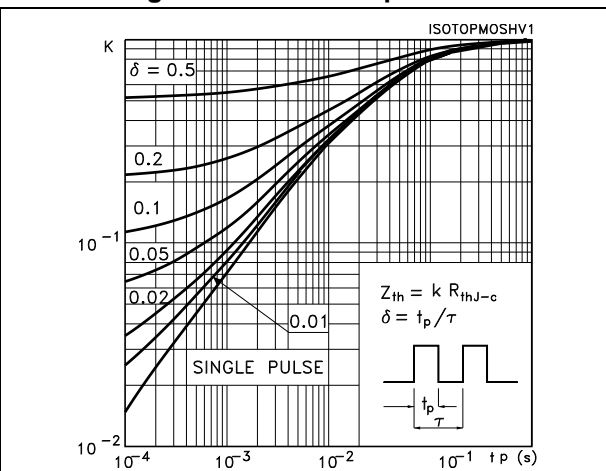


Figure 4. Output characteristics

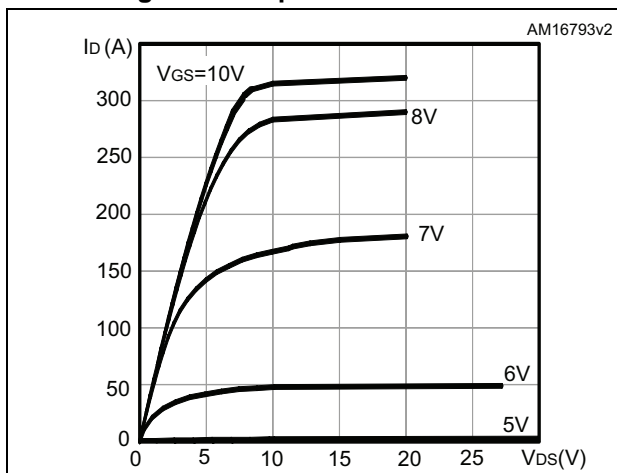


Figure 5. Transfer characteristics

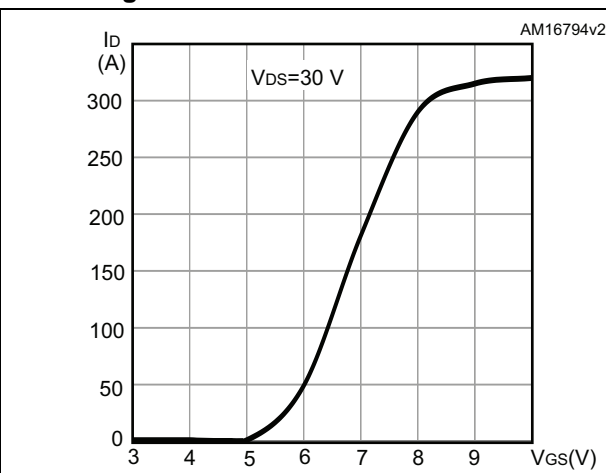


Figure 6. Normalized V_{DS} vs temperature

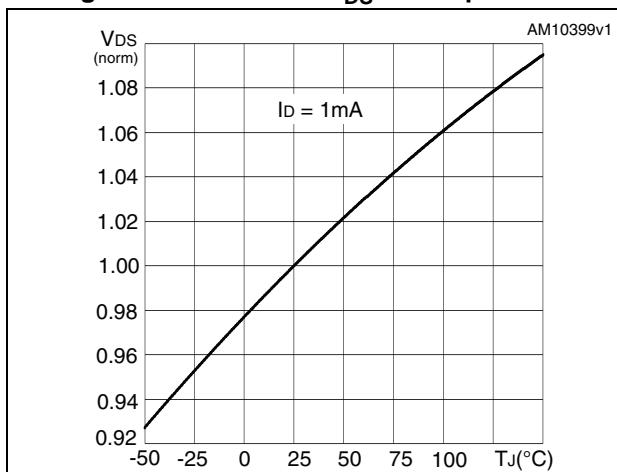


Figure 7. Static drain-source on-resistance

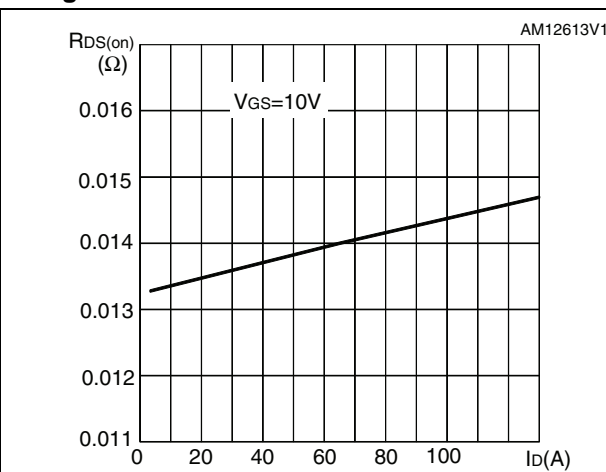


Figure 8. Gate charge vs gate-source voltage

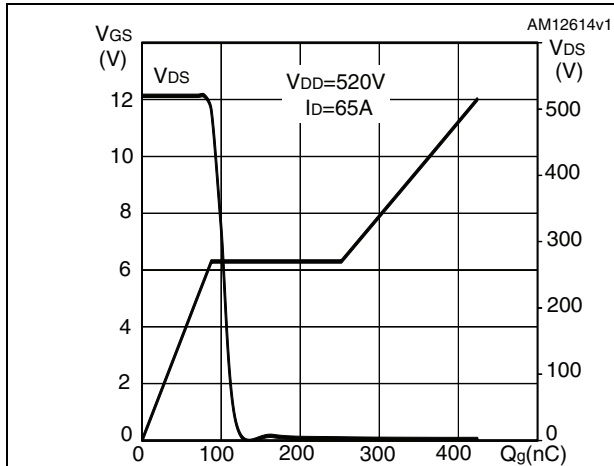


Figure 9. Capacitance variations

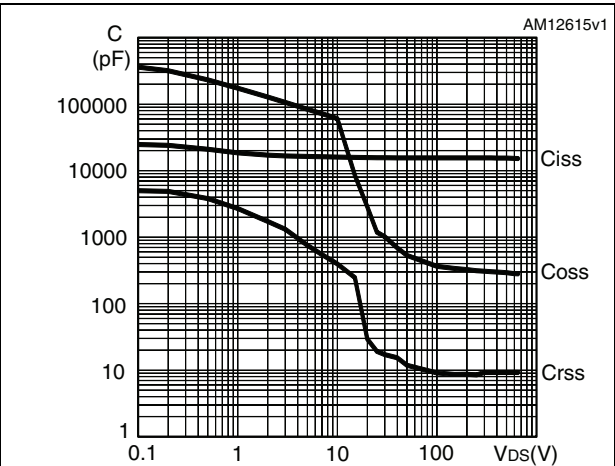


Figure 10. Normalized gate threshold voltage vs temperature

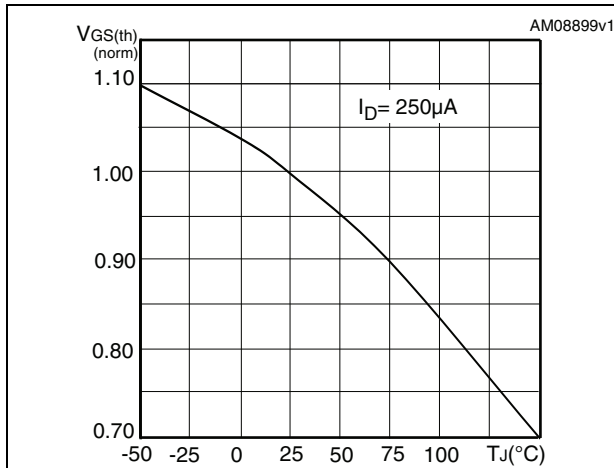


Figure 11. Normalized on-resistance vs temperature

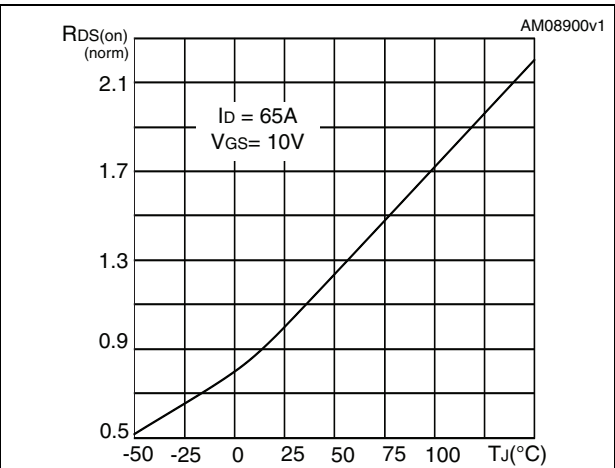


Figure 12. Output capacitance stored energy

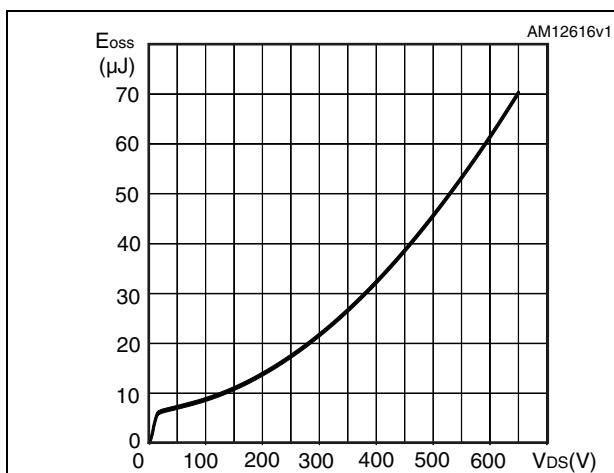
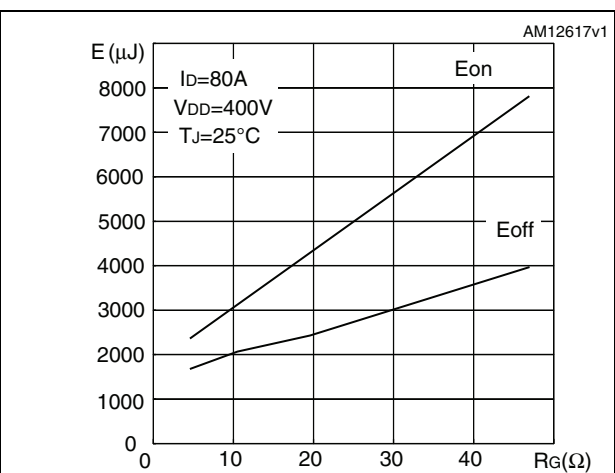


Figure 13. Switching losses vs gate resistance (1)



1. Eon including reverse recovery of a SiC diode.

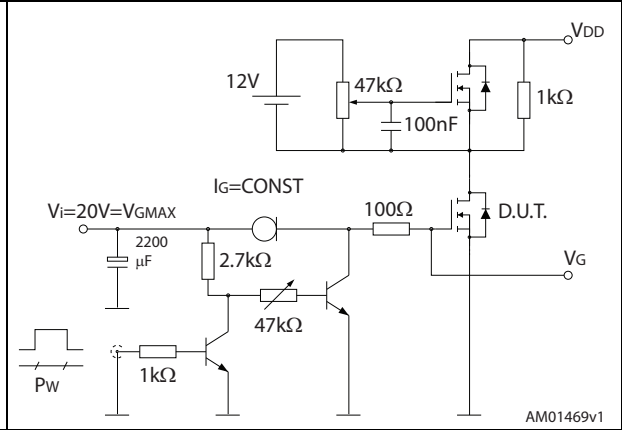
3 Test circuits

Figure 14. Switching times test circuit for resistive load



AM01468v1

Figure 15. Gate charge test circuit



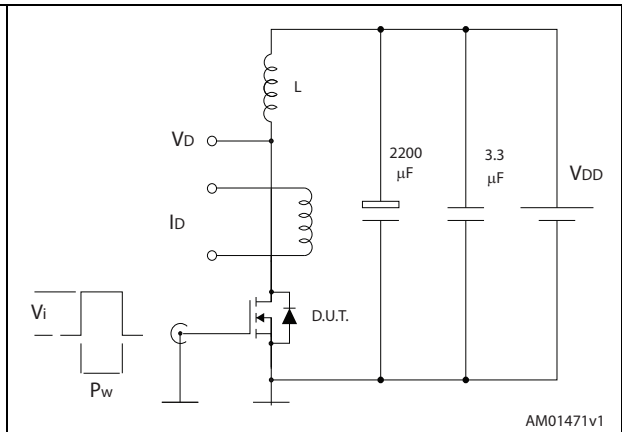
AM01469v1

Figure 16. Test circuit for inductive load switching and diode recovery times



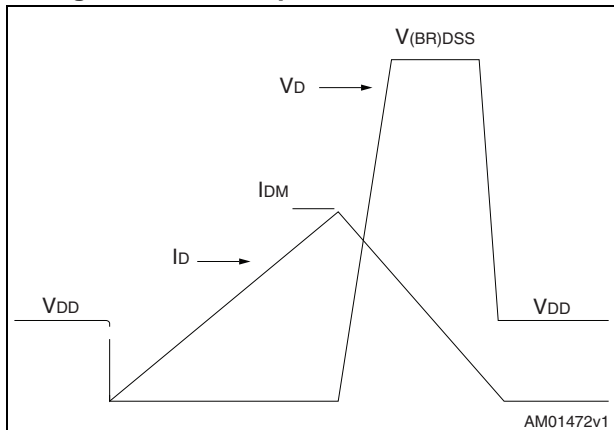
AM01470v1

Figure 17. Unclamped inductive load test circuit



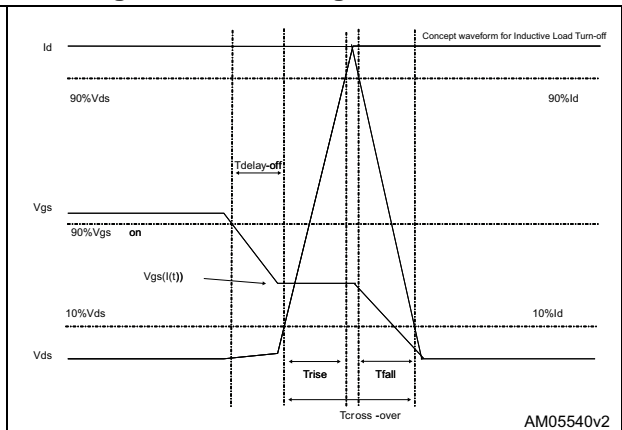
AM01471v1

Figure 18. Unclamped inductive waveform



AM01472v1

Figure 19. Switching time waveform



AM05540v2

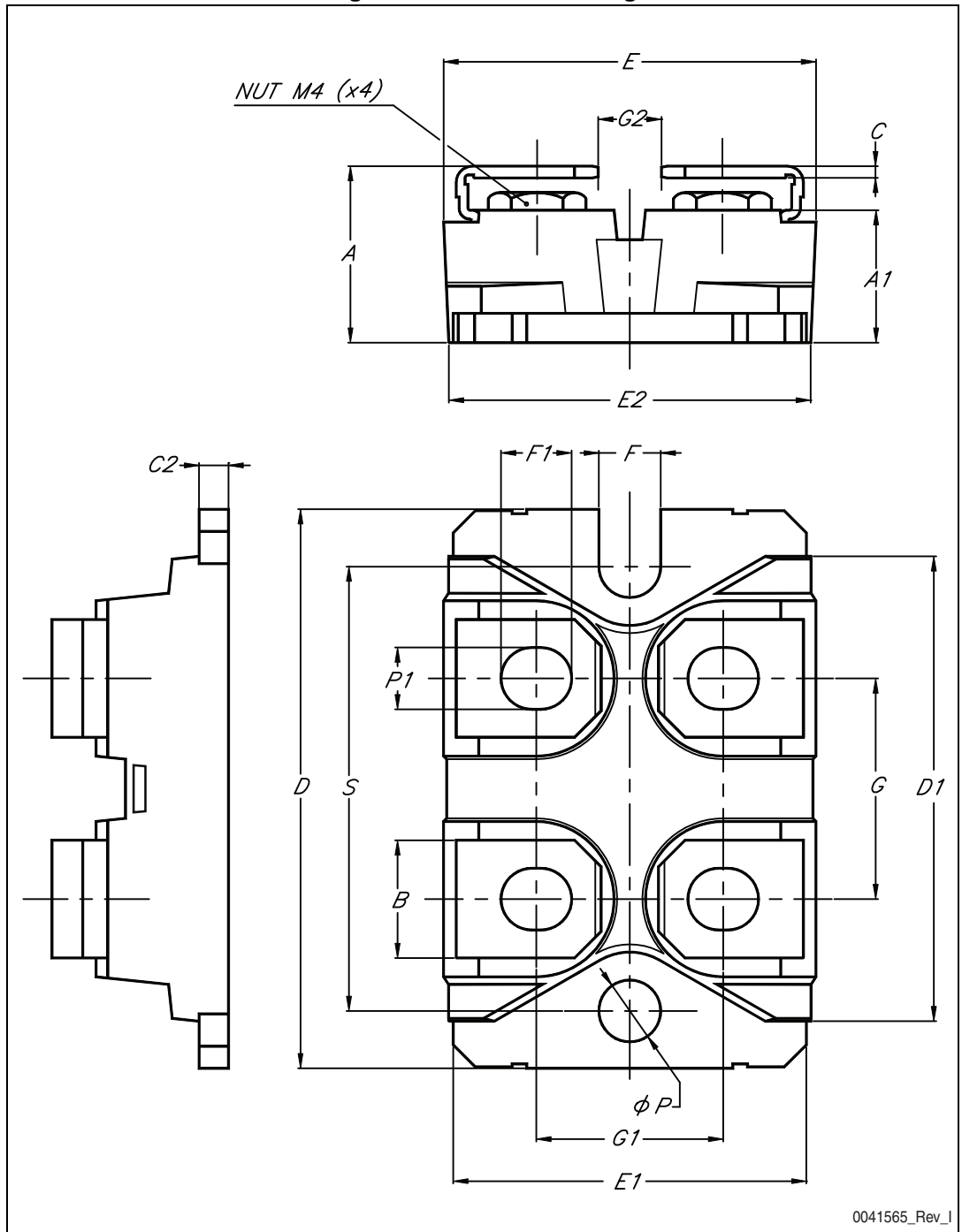
4 Package mechanical data

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Table 8. ISOTOP mechanical data

| Dim. | mm | | |
|------|-------|-------|-------|
| | Min. | Typ. | Max. |
| A | 11.80 | | 12.20 |
| A1 | 8.90 | | 9.10 |
| B | 7.80 | | 8.20 |
| C | 0.75 | | 0.85 |
| C2 | 1.95 | | 2.05 |
| D | 37.80 | | 38.20 |
| D1 | 31.50 | | 31.70 |
| E | 25.15 | | 25.50 |
| E1 | 23.85 | | 24.15 |
| E2 | | 24.80 | |
| G | 14.90 | | 15.10 |
| G1 | 12.60 | | 12.80 |
| G2 | 3.50 | | 4.30 |
| F | 4.10 | | 4.30 |
| F1 | 4.60 | | 5 |
| φP | 4 | | 4.30 |
| P1 | 4 | | 4.40 |
| S | 30.10 | | 30.30 |

Figure 20. ISOTOP drawing



0041565_Rev_I

5 Revision history

Table 9. Document revision history

| Date | Revision | Changes |
|-------------|----------|------------------|
| 13-Aug-2013 | 1 | Initial release. |

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